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Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, IEEE CNF = IEEE Standard

1. Analysis of a statistics counter architecture

Devavrat Shah; Sundar Iyer; Balaji Prabhakar; McKeown, N.; Hot Interconnects 9, 2001. 22-24 Aug. 2001 Page(s):107 - 111

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2. A data-centric concurrency control mechanism for three tier systems

Janaki Ram, D.; Chandra Sekhar, N.S.K.; Uma Mahesh, M.; Systems, Man, and Cybernetics, 2001 IEEE International Conference on Volume 4, 7-10 Oct. 2001 Page(s):2402 - 2407 vol.4

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3. A Josephson ternary memory circuit

Morisue, M.; Endo, J.; Morooka, T.; Shimizu, N.; Sakamoto, M.; Multiple-Valued Logic, 1998. Proceedings. 1998 28th IEEE International Symposium on 27-29 May 1998 Page(s):19 - 24

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Li, W.; He, Z.; Knoll, G.F.; Wehe, D.K.; Nuclear Science Symposium Conference Record, 2000 IEEE Volume 1, 15-20 Oct. 2000 Page(s):4/30 vol.1

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